

FORM PTO-1449 (Modified)

(Use several sheets if necessary)

Application Number

Applicants: James Chingwei Li, et al

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## U.S. PATENT DOCUMENTS

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# FOREIGN PATENT DOCUMENTS

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### Translation

**Yes**

No

| OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) |  |   |  |
|--|--|---|--|
|  |  | F. C. Colson, R. L. Bates, M. F. Bishop, et al. |  |

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E. G. Colgan, R.J. Polastre, M. Takeichi and R.L. Wisniew, Thin-Film-Transistor Process-Characterization Test Structures, February 12, 1998, <http://www.research.ibm.com/journal/rd/423/polastre.txt>

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